# **MOSFET** – N-Channel, **UniFET**<sup>™</sup>

**200 V, 16 A, 125 m** $\Omega$ 

# FDD18N20LZ

#### Description

UniFET MOSFET is ON Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.

#### Features

- $R_{DS(on)} = 125 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$
- Low Gate Charge (Typ. 30 nC)
- Low C<sub>RSS</sub> (Typ. 25 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Improved Capability
- These Device is Pb-Free and is RoHS Compliant
- Applications
- LED TV
- Consumer Appliances
- Uninterruptible Power Supply



# **ON Semiconductor®**

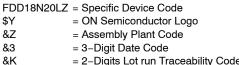
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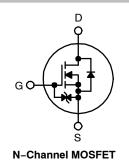
DPAK3 (TO-252 3 LD) CASE 369AS







= 2-Digits Lot run Traceability Code



#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 6 of this data sheet.

#### **MOSFET MAXIMUM RATINGS** (T<sub>C</sub> = $25^{\circ}$ C unless otherwise noted)

Symbol	Parameter		FDD18N20LZ	Unit
V <sub>DSS</sub>	Drain to Source Voltage		200	V
V <sub>GSS</sub>	Gate to Source Voltage		±20	V
Ι <sub>D</sub>	Drain Current	Continuous (T <sub>C</sub> = 25°C)	16	А
		Continuous (T <sub>C</sub> = 100°C)	9.6	1
I <sub>DM</sub>	Drain Current (Note 1)	Pulsed	64	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		320	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)		16	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		8.9	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		10	V/ns
P <sub>D</sub>	Power Dissipation	(T <sub>C</sub> = 25°C)	89	W
		Derate above 25°C	0.7	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		–55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. L = 2.5 mH,  $I_{AS}$  = 16 A,  $V_{DD}$  = 50 V,  $R_G$  = 25  $\Omega$ , starting  $T_J$  = 25°C. 3.  $I_{SD} \le 16 \text{ A}$ , di/dt  $\le 200 \text{ A}/\mu$ s,  $V_{DD} \le BV_{DSS}$ , starting  $T_J$  = 25°C.

#### THERMAL CHARACTERISTICS

Symbol	Parameter	FDD18N20LZ	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	1.4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	83	

## ELECTRICAL CHARACTERISTICS (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D$ = 250 $\mu A,V_{GS}$ = 0 V, $T_J$ = 25°C	200	-	-	V
$\Delta {\sf BV}_{\sf DSS}$ / $\Delta$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 µA, Referenced to 25°C	-	0.2	-	V/°C
T <sub>J</sub> I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 200 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1	μΑ
		$V_{DS} = 160 \text{ V}, \text{ T}_{C} = 125^{\circ}\text{C}$	-	-	10	
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS}$ = ±16 V, $V_{DS}$ = 0 V	Ι	-	±10	μΑ
ON CHARAC	CTERISTICS					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ = 250 $\mu$ A	1.0	-	2.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS}$ = 10 V, I <sub>D</sub> = 8 A	-	0.10	0.125	Ω
		$V_{GS} = 5 \text{ V}, \text{ I}_{D} = 8 \text{ A}$	-	0.11	0.13	
<b>g</b> fs	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 2 A	-	11	-	S
DYNAMIC C	HARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V f = 1 MHz	-	1185	1575	pF
C <sub>oss</sub>	Output Capacitance	f = 1 MHz	-	190	255	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	25	40	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V	$V_{DS}$ = 200 V, I <sub>D</sub> = 16 A, V <sub>GS</sub> = 10 V (Note 4)	-	30	40	nC
Q <sub>gs</sub>	Gate to Source Gate Charge		-	3.5	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		-	8.5	-	nC
SWITCHING	CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 100 \text{ V}, \text{ I}_{D} = 16 \text{ A}, \text{ V}_{GS} = 10 \text{ V},$	-	15	40	ns
t <sub>r</sub>	Turn–On Rise Time	$R_{G} = 25 \Omega$ (Note 4)	-	20	50	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		-	135	280	ns
t <sub>f</sub>	Turn-Off Fall Time		-	50	110	ns
DAIN-SOUR	CE DIODE CHARACTERISTICS					
۱ <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	16	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	64	Α
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	rd Voltage $V_{GS} = 0 V, I_{SD} = 4 A$		-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 V, I_{SD} = 4 A$	-	105	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/µs	-	0.4	_	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Essentially independent of operating temperature typical characteristics.

### **TYPICAL PERFORMANCE CHARACTERISTICS**

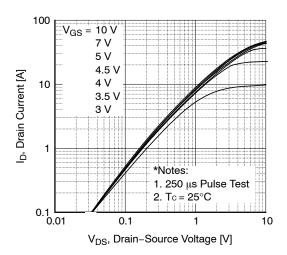
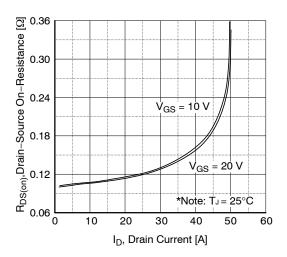
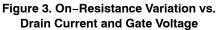


Figure 1. On–Region Characteristics





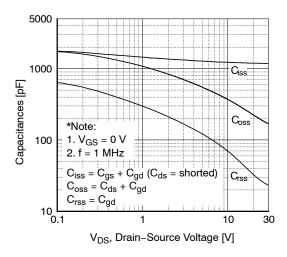
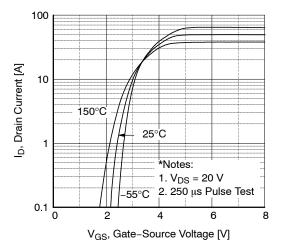


Figure 5. Capacitance Characteristics



**Figure 2. Transfer Characteristics** 

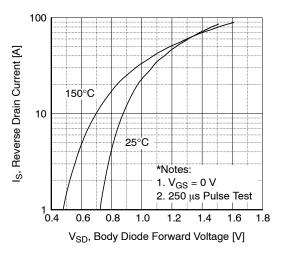


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

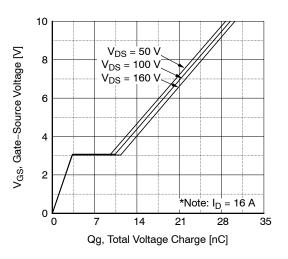
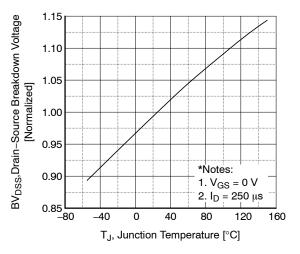
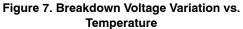


Figure 6. Gate Charge Characteristics

## TYPICAL PERFORMANCE CHARACTERISTICS (Continued)





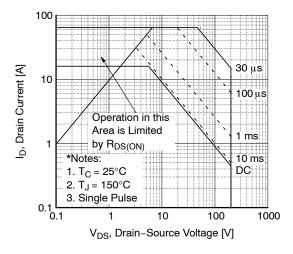


Figure 9. Maximum Safe Operating Area

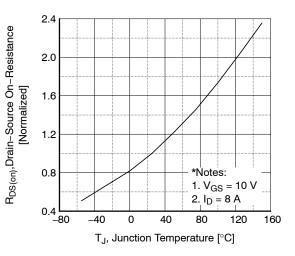


Figure 8. On–Resistance Variation vs. Temperature

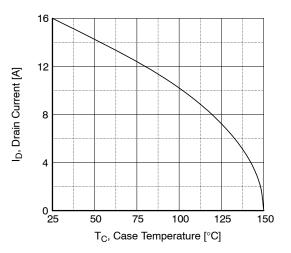


Figure 10. Maximum Drain Current vs. Case Temperature

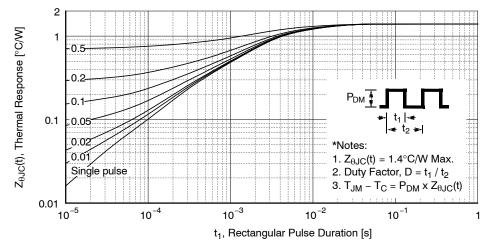


Figure 11. Transient Thermal Response Curve

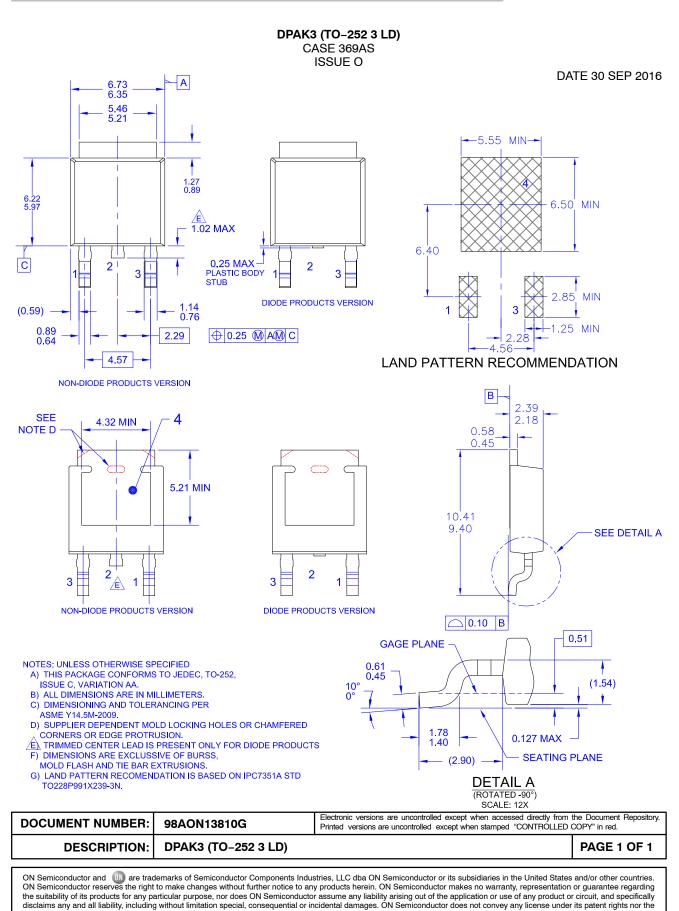
#### PACKAGE MARKING ANDORDERING INFORMATION

Part Number	Top Mark	Package	Reel Size	Tape Width	<b>Shipping</b> <sup>†</sup>
FDD18N20LZ	FDD18N20LZ	DPAK3 (TO–252 3 LD) (Pb–Free)	330 mm	16 mm	2500 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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